Progress in Surface Science

An International Review Journal

EDITOR: Professor Sydney G. Davison

AUTHOR AND SUBJECT INDEX

Volume 34, 1990

PERGAMON PRESS

New York / Oxford / Frankfurt
Seoul / Sydney / Tokyo

Progress in Surface Science

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Publishing, Subscription and Advertising Offices: Pergamon Press, Inc., Fairview Park, Elmsford, New York 10523, U.S.A. and Pergamon Press plc, Headington Hill Hall, Oxford OX3 OBW, England.

Published Monthly: 3 volumes per year, 4 issues per volume. Annual institutional Subscription rate (1991): DM900.00; Two-year institutional rate (1991/92): DM1710.00; Personal subscription rate for those whose library subscribes at the regular rate: DM265.00. Prices are subject to change without notice. Notify 8 weeks in advance of address change with a copy of the subscription mailing label. *Microform subscriptions:* Information available upon request. Subscription rates for Japan include despatch by air and prices are available on application.

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The Item-Fee Code for this publication is: 0079-6816/91 $0.00 + .50.

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(00700)
1991: Volume 11 (4 issues)
Annual subscription (1991) **DM 400.00**
Two-year rate (1991/92) **DM 760.00**
ISSN: 0734-743X

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Pergamon Press plc, Headington Hill Hall, Oxford OX3 0BW, UK
Pergamon Press, Inc., Maxwell House, Fairview Park, Elmsford NY 10523, USA

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(00220)
1991: Volume 39 (8 issues)
Annual subscription (1991) **DM 990.00**
Two-year rate (1991/92) **DM 1881.00**
ISSN: 0022-5096

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Pergamon Press, Inc., Maxwell House, Fairview Park, Elmsford NY 10523, USA

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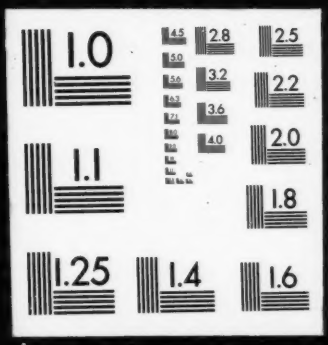
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